P-Channel Enhancement Mode Field Effect Transistor

#### **General Description**

The AON4413 uses advanced trench technology to provide excellent  $R_{DS(ON)}$  with low gate charge. This device is suitable for use as a load switch or in PWM applications. Standard product AON4413 is Pb-free (meets ROHS & Sony 259 specifications).

#### **Features**

 $V_{DS}(V) = -30V$ 

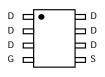
 $I_D = -6.5A$   $(V_{GS} = -10V)$ 

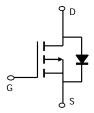
 $R_{DS(ON)}$  < 46m $\Omega$  ( $V_{GS}$  = -10V)

 $R_{DS(ON)}$  < 60m $\Omega$  ( $V_{GS}$  = -6V)









Absolute Maximum Ratings T <sub>A</sub> =25°C unless otherwise noted							
Parameter		Symbol	10 Sec	Steady State	Units		
Drain-Source Voltage		$V_{DS}$	-30		V		
Gate-Source Voltage		$V_{GS}$	±20		V		
Continuous Drain Current <sup>A</sup>	T <sub>A</sub> =25°C		-6.5	-4.7			
	T <sub>A</sub> =70°C	I <sub>D</sub>	-5.3	-3.7	Α		
Pulsed Drain Current <sup>B</sup>		I <sub>DM</sub>	-25				
Power Dissipation <sup>A</sup>	T <sub>A</sub> =25°C	В	3.1	1.6	W		
	T <sub>A</sub> =70°C	$P_D$	2.0	1.0	VV		
Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>STG</sub>	-55 to 150		°C		

Thermal Characteristics						
Parameter	Symbol	Тур	Max	Units		
Maximum Junction-to-Ambient A	t ≤ 10s		34	40	°C/W	
Maximum Junction-to-Ambient A	Steady State	teady State		80	°C/W	
Maximum Junction-to-Lead <sup>C</sup>	Steady State	$R_{\scriptscriptstyle{ hetaJL}}$	20	25	°C/W	



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#### Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)

Symbol	Parameter	Conditions		Min	Тур	Max	Units
STATIC F	PARAMETERS						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$		-30			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = -30V, V_{GS} = 0V$				-1	μА
			$T_J = 55^{\circ}C$			-5	μΛ
$I_{GSS}$	Gate-Body leakage current	$V_{DS} = 0V, V_{GS} = \pm 20V$	,			±100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS} I_{D} = -250 \mu A$		-1.5	-2	-2.5	V
$I_{D(ON)}$	On state drain current	$V_{GS} = -10V, V_{DS} = -5V$	1	-25			Α
	Static Drain-Source On-Resistance	$V_{GS} = -10V, I_D = -6.5A$			38	46	mΩ
R <sub>DS(ON)</sub>			T <sub>J</sub> =125°C		54	65	1115.2
		$V_{GS} = -6V, I_D = -5.3A$			48	60	mΩ
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = -5V, I_{D} = -6.5A$			11		S
$V_{SD}$	Diode Forward Voltage	$I_S = -1A, V_{GS} = 0V$			0.77	-1	V
Is	Maximum Body-Diode Continuous Current					-3	Α
DYNAMIC	PARAMETERS						
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =-15V, f=1MHz			668	830	pF
C <sub>oss</sub>	Output Capacitance				126		pF
C <sub>rss</sub>	Reverse Transfer Capacitance				92		pF
$R_g$	Gate resistance	$V_{GS}$ =0V, $V_{DS}$ =0V, f=1MHz			6	9	Ω
SWITCHI	NG PARAMETERS						
Q <sub>g</sub> (10V)	Total Gate Charge (10V)	V <sub>GS</sub> =-10V, V <sub>DS</sub> =-15V, I <sub>D</sub> =-6.5A			12.7	17	nC
Q <sub>g</sub> (4.5V)	Total Gate Charge (4.5V)				6.4	8.5	nC
$Q_{gs}$	Gate Source Charge				2		nC
$Q_{gd}$	Gate Drain Charge				4		nC
t <sub>D(on)</sub>	Turn-On DelayTime	$V_{GS}$ =-10V, $V_{DS}$ =-15V, $R_L$ =2.3 $\Omega$ , $R_{GEN}$ =3 $\Omega$			7.7		ns
t <sub>r</sub>	Turn-On Rise Time				6.8		ns
$t_{D(off)}$	Turn-Off DelayTime				20		ns
t <sub>f</sub>	Turn-Off Fall Time				10		ns
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =-6.5A, dI/dt=100A/	μs		22	30	ns
$Q_{rr}$	Body Diode Reverse Recovery Charg	ge I <sub>F</sub> =-6.5A, dI/dt=100A/μs			15		nC

A: The value of R  $_{0,JA}$  is measured with the device mounted on 1in  $^2$  FR-4 board with 2oz. Copper, in a still air environment with T  $_A$  = 25°C. The value in any a given application depends on the user's specific board design. The current rating is based on the t  $_{-}$   $\leq$  10s thermal resistance rating.

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B: Repetitive rating, pulse width limited by junction temperature.

C. The R  $_{\theta JA}$  is the sum of the thermal impedence from junction to lead R  $_{\theta JL}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using < 300  $\mu s$  pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in  $^2$  FR-4 board with 2oz. Copper, in a still air environment with T  $_A$ =25°C. The SOA curve provides a single pulse rating.



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#### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

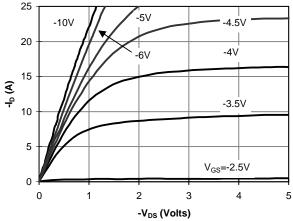


Figure 1: On-Region Characteristics

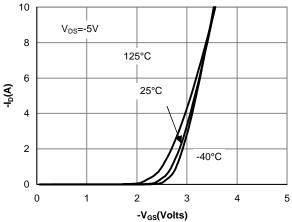


Figure 2: Transfer Characteristics

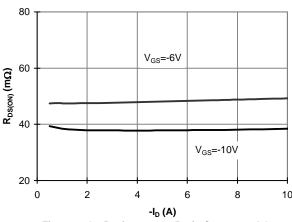


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

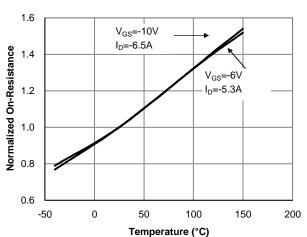


Figure 4: On-Resistance vs. Junction Temperature

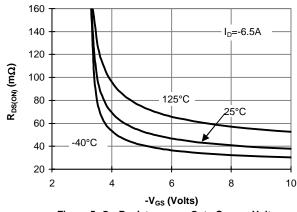


Figure 5: On-Resistance vs. Gate-Source Voltage

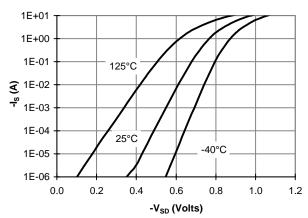


Figure 6: Body-Diode Characteristics



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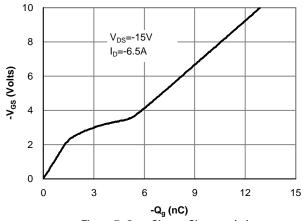


Figure 7: Gate-Charge Characteristics

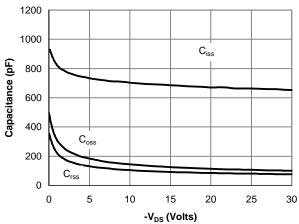


Figure 8: Capacitance Characteristics

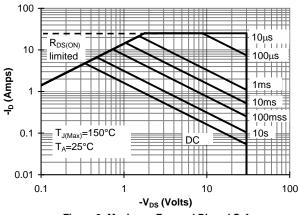
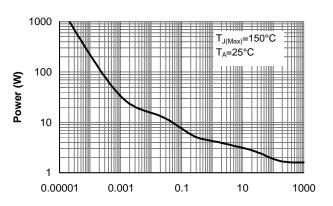


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)



Pulse Width (s)
Figure 10: Single Pulse Power Rating Junction-to
Ambient (Note E)

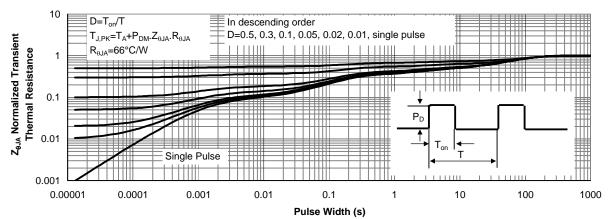


Figure 11: Normalized Maximum Transient Thermal Impedance(Note E)